

Supporting Information for

Structure dependent photostability of ITIC and ITIC-4F

Laura Ciammaruchi,^{*a} Osnat Zapata-Arteaga,^a Edgar Guitierrez,^b Jaime Martín^{b,c} and Mariano Campoy-Quiles^{*a}

^a Institute of Materials Science of Barcelona (ICMAB-CSIC), Campus of the UAB, 08193,

Bellaterra, Spain

^b POLYMAT and Polymer Science and Technology Department, Faculty of Chemistry,

University of the Basque Country UPV/EHU, Manuel de Lardizabal 3, 20018, Donostia-

San Sebastián, Spain

^c Ikerbasque, Basque Foundation for Science, E-48011, Bilbao, Spain

^{*}Corresponding authors. E-mails: lciammaruchi@icmab.es; mcampoy@icmab.es

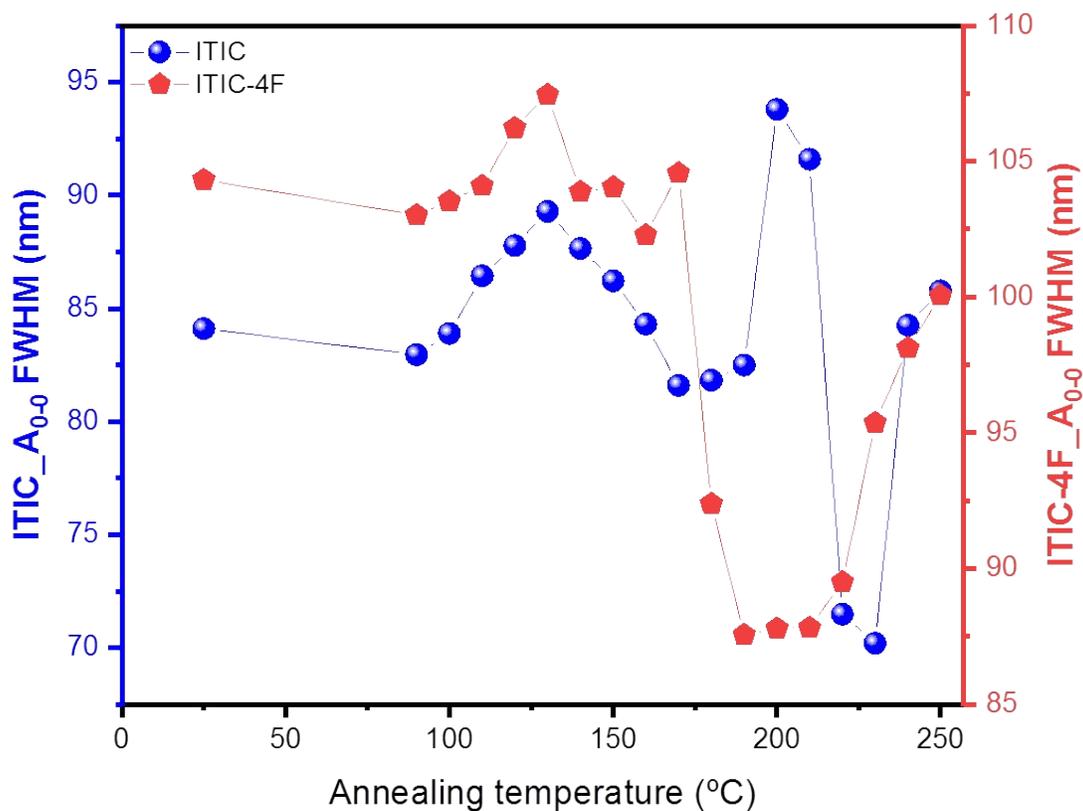


Figure S1. Full-Width-Half-Maximum (FWHM) values as function of the annealing temperatures. Values extrapolated from UV-vis absorption data for ITIC (balloon) and ITIC-4F (pentagon).

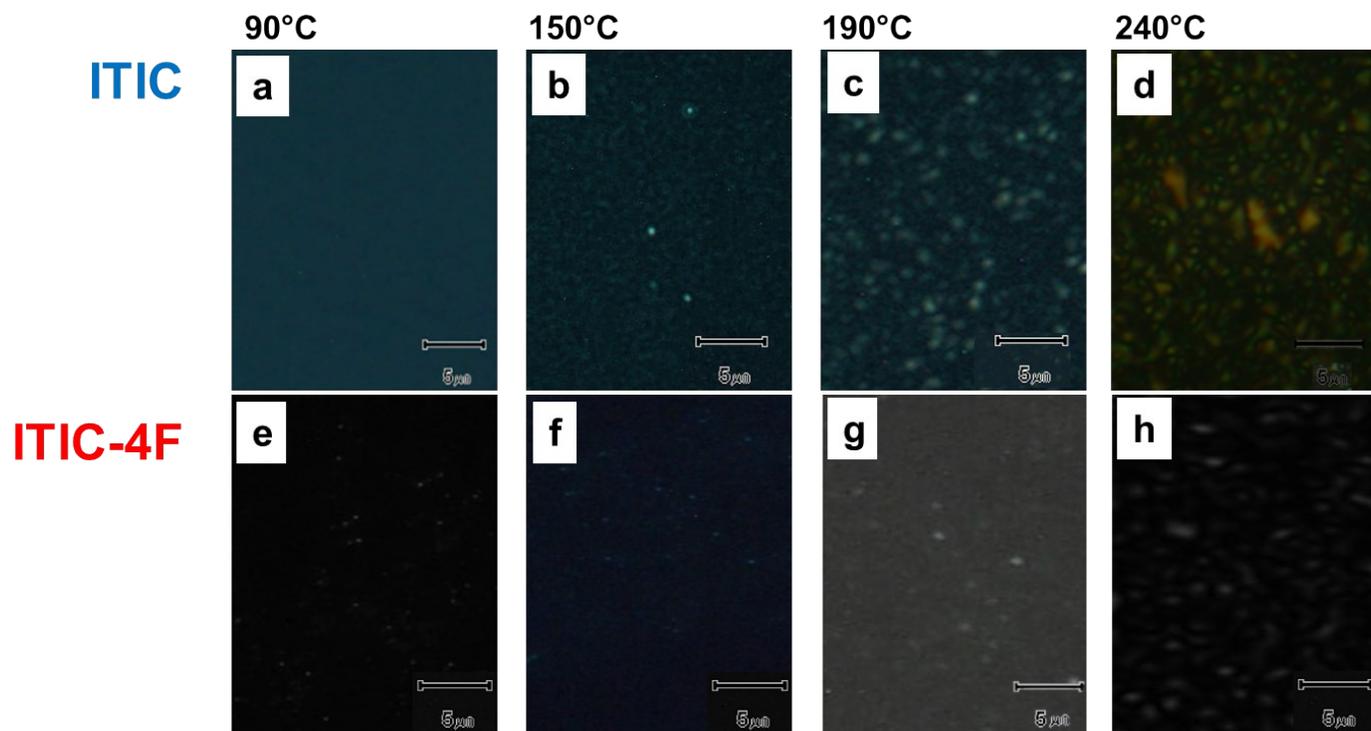


Figure S2. Polarized optical microscopy images of ITIC (upper row) and ITIC-4F (lower row) thin films deposited on ITO-covered glass and annealed at 90°C (a,e), 150°C (b,f), 190°C (c,g) and 240°C (d,h).

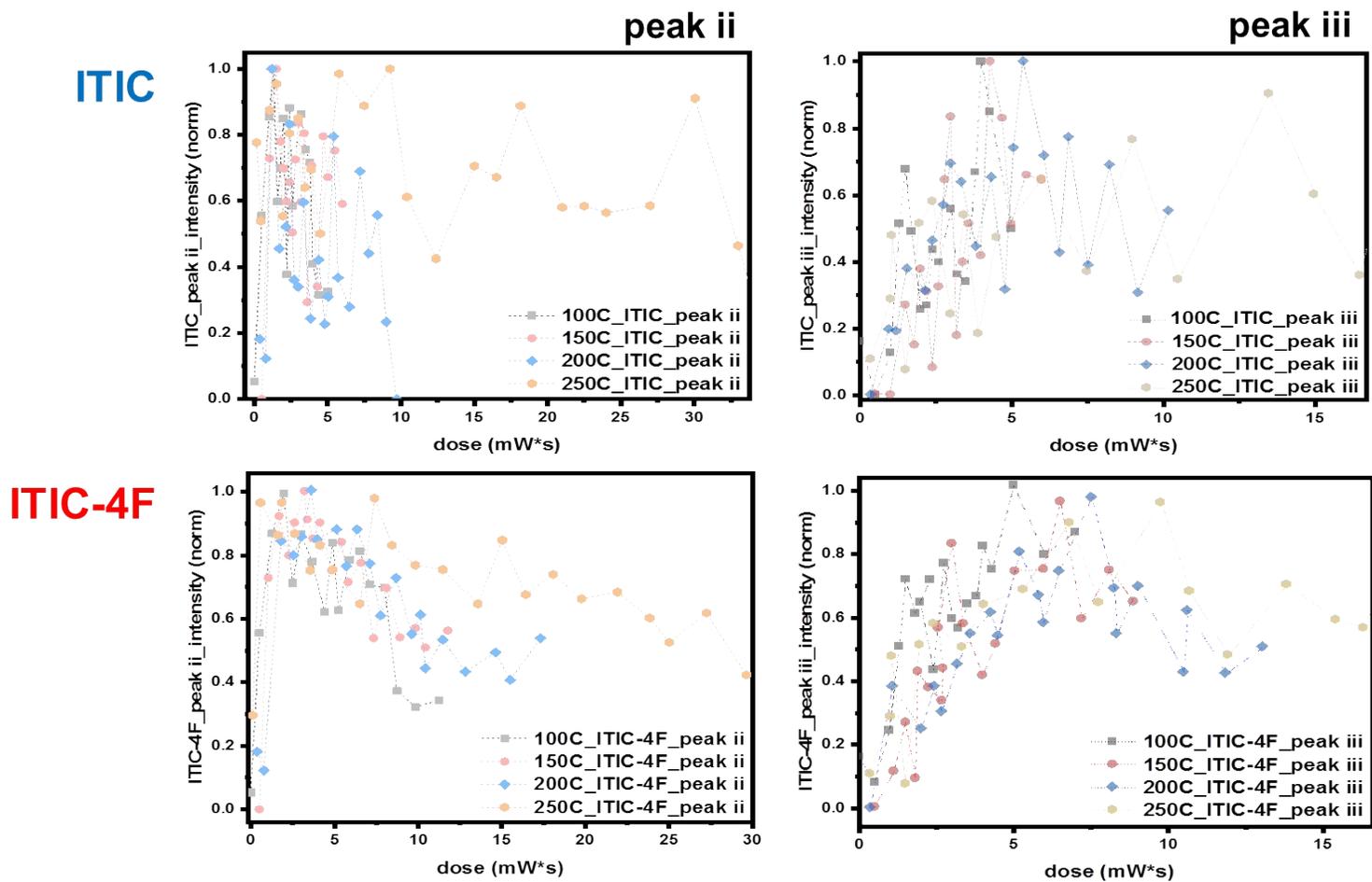


Figure S3. Dose-dependent Raman decay for peaks ii and iii, for ITIC (upper row) and ITIC-4F (lower row) annealed at different temperatures.

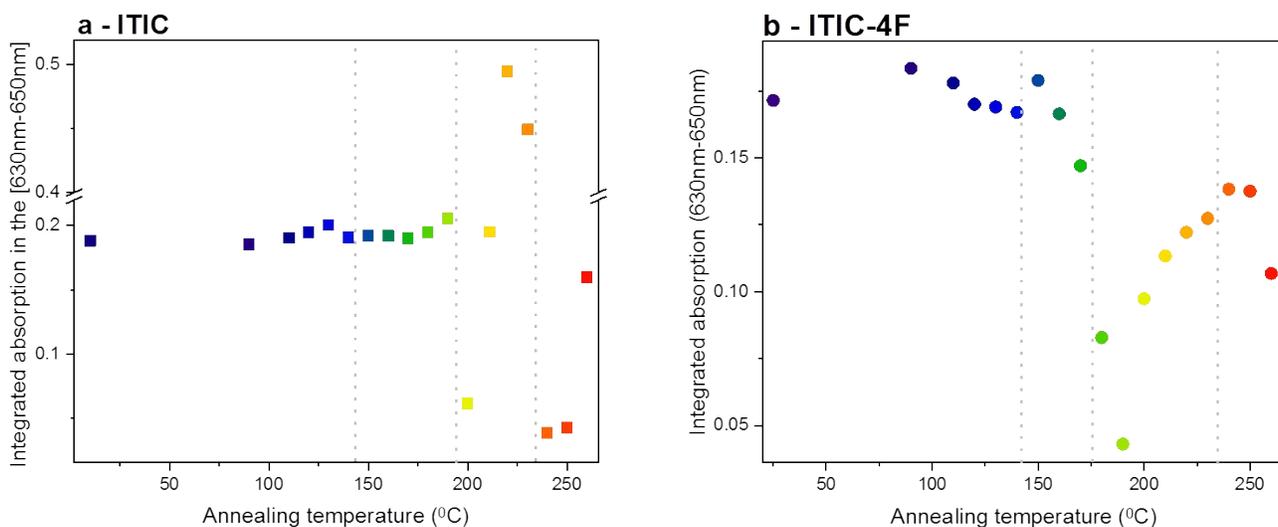


Figure S4. Integrated absorption values in the (630nm-650nm) range against the materials' annealing temperature, for ITIC (a) and ITIC-4F (b).

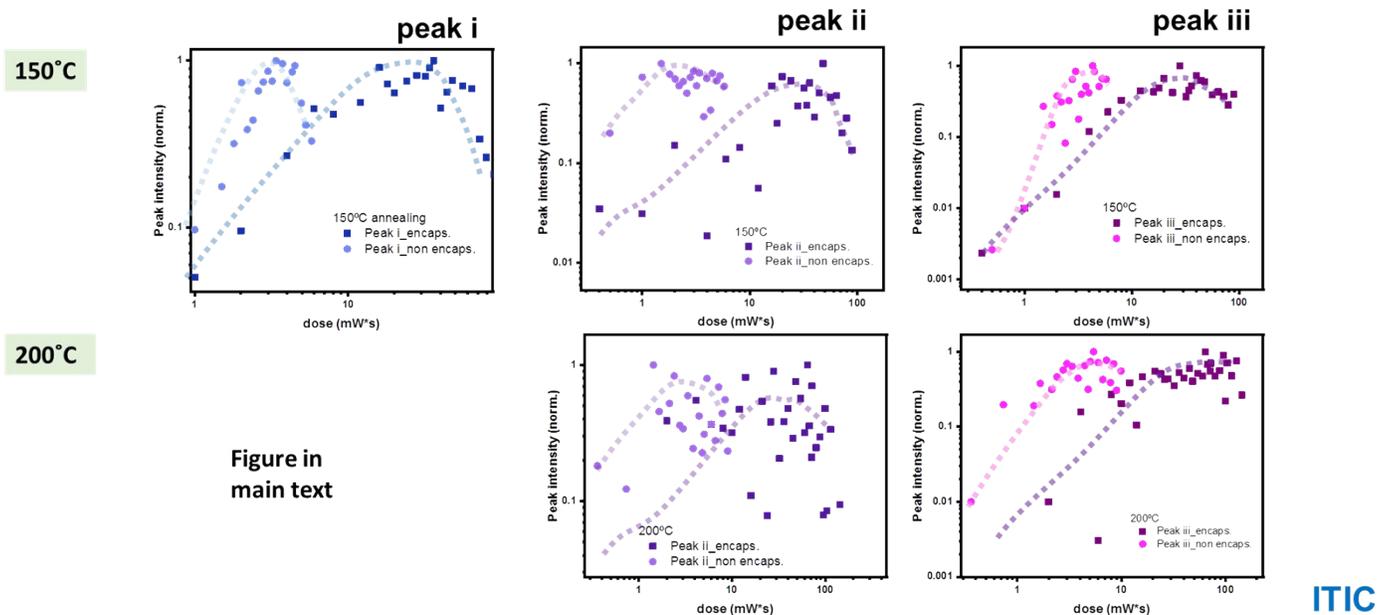


Figure S5. Dose-dependent Raman decay for peaks i, ii and iii, for encapsulated ITIC annealed at 150°C (upper row) and 200°C (lower row). Dashed lines are just a guide for the eye.

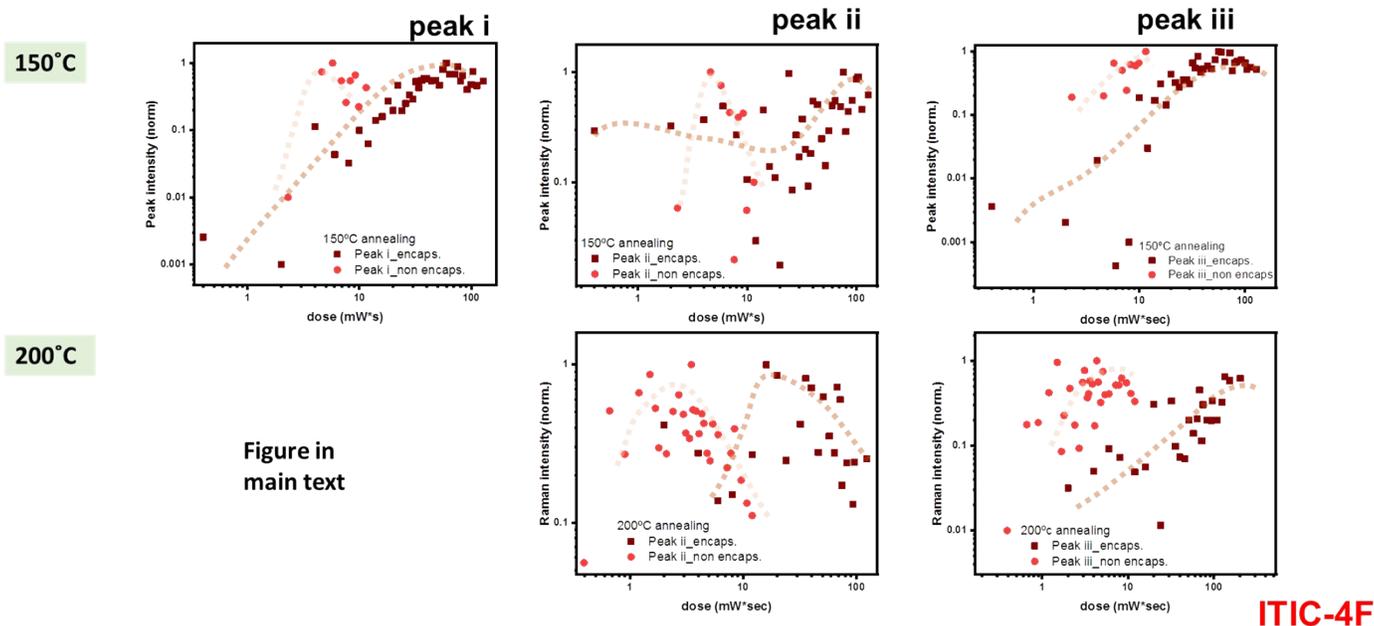


Figure S6. Dose-dependent Raman decay for peaks i, ii and iii, for encapsulated ITIC-4F annealed at 150°C (upper row) and 200°C (lower row). Dashed lines are just a guide for the eye.

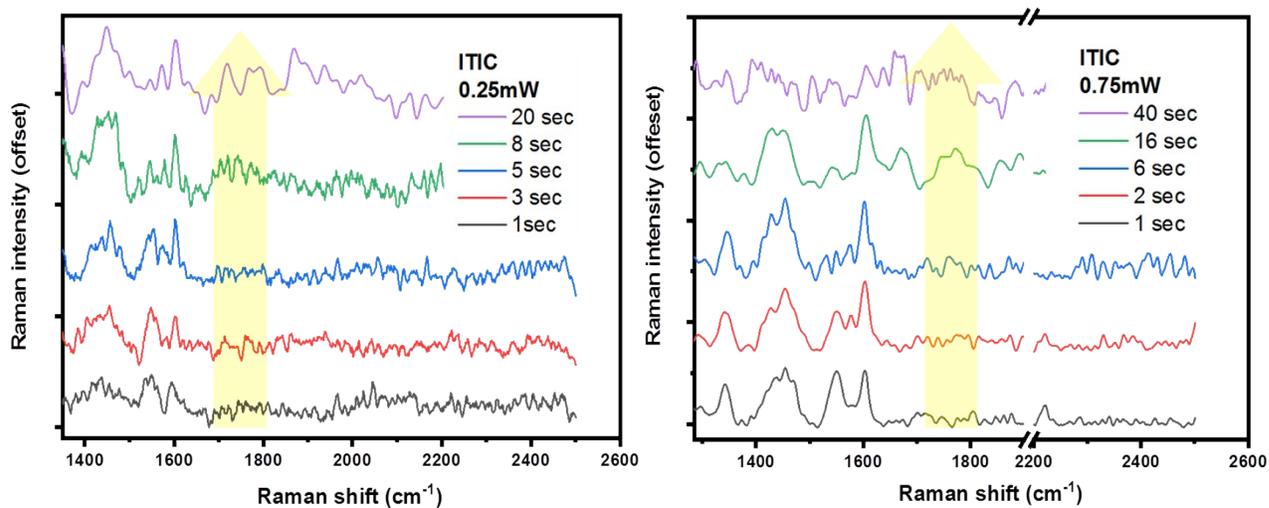
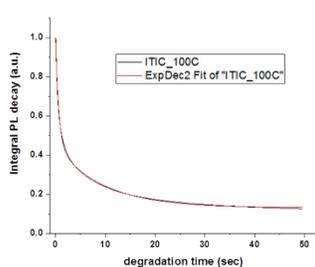
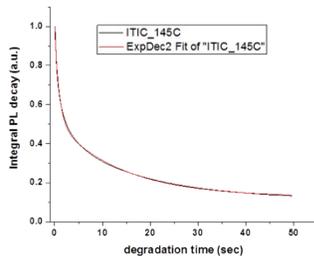


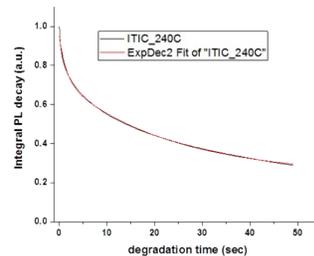
Figure S7. Raising vibrational mode in the ($1700 \text{ cm}^{-1} - 1850 \text{ cm}^{-1}$) range, for ITIC probed at two different powers.



Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot L26A_PL_0.25mW_sum centered at 760
 y0 $0.12991 \pm 5.10095E-4$
 A1 0.543 ± 0.00404
 t1 0.43425 ± 0.00948
 A2 0.32031 ± 0.00204
 t2 2.74175 ± 0.09702
 Reduced Chi-Sqr 3.13237E-5
 R-Square (COD) 0.99743
 Adj. R-Square 0.99741



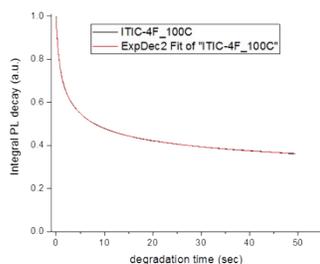
Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot ITIC_27A
 y0 $0.12653 \pm 7.79248E-4$
 A1 0.47956 ± 0.00334
 t1 0.53277 ± 0.01293
 A2 0.39043 ± 0.00163
 t2 2.61992 ± 0.12758
 Reduced Chi-Sqr 2.78028E-5
 R-Square (COD) 0.99842
 Adj. R-Square 0.99841



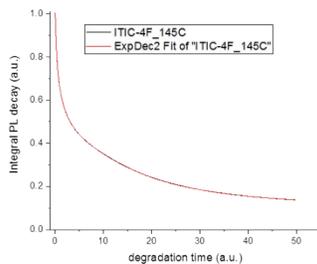
Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot ITIC_288
 y0 0.23753 ± 0.00194
 A1 0.22117 ± 0.00265
 t1 0.44474 ± 0.03692
 A2 0.48914 ± 0.00128
 t2 4.45672 ± 0.26832
 Reduced Chi-Sqr 2.34368E-5
 R-Square (COD) 0.99877
 Adj. R-Square 0.99876

ITIC

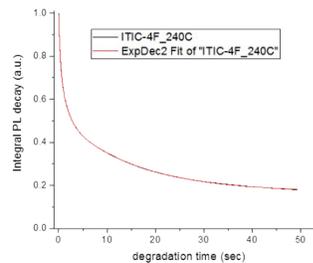
Figure S8. Fitting curves and parameters for ITIC integrated PL decay curve under *in-situ* 633nm laser degradation, for three sample annealing temperatures.



Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot ITIC-4F_31A
 y0 $0.33684 \pm 8.71231E-4$
 A1 0.23921 ± 0.00178
 t1 3.67161 ± 0.00666
 A2 0.22879 ± 0.00135
 t2 2.74175 ± 0.04881
 Reduced Chi-Sqr 9.89952E-7
 R-Square (COD) 0.99989
 Adj. R-Square 0.99989



Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot ITIC-4F_32A_0.25mW_785 sum
 y0 $0.11944 \pm 1.78346E-4$
 A1 0.19257 ± 0.00294
 t1 1.29745 ± 0.00524
 A2 0.25895 ± 0.00282
 t2 2.61992 ± 0.01302
 Reduced Chi-Sqr 7.30322E-7
 R-Square (COD) 0.99996
 Adj. R-Square 0.99996



Model ExpDec2
 Equation $y = A1 \cdot \exp(-x/t1) + A2 \cdot \exp(-x/t2) + y0$
 Plot ITIC-4F_33B
 y0 $0.1682 \pm 1.4818E-4$
 A1 0.2 ± 0.00195
 t1 1.41192 ± 0.00359
 A2 0.27846 ± 0.00179
 t2 4.45672 ± 0.00997
 Reduced Chi-Sqr 5.3057E-7
 R-Square (COD) 0.99996
 Adj. R-Square 0.99996

ITIC-4F

Figure S9. Fitting curves and parameters for ITIC-4F integrated PL decay curve under *in-situ* 633nm laser degradation, for three sample annealing temperatures

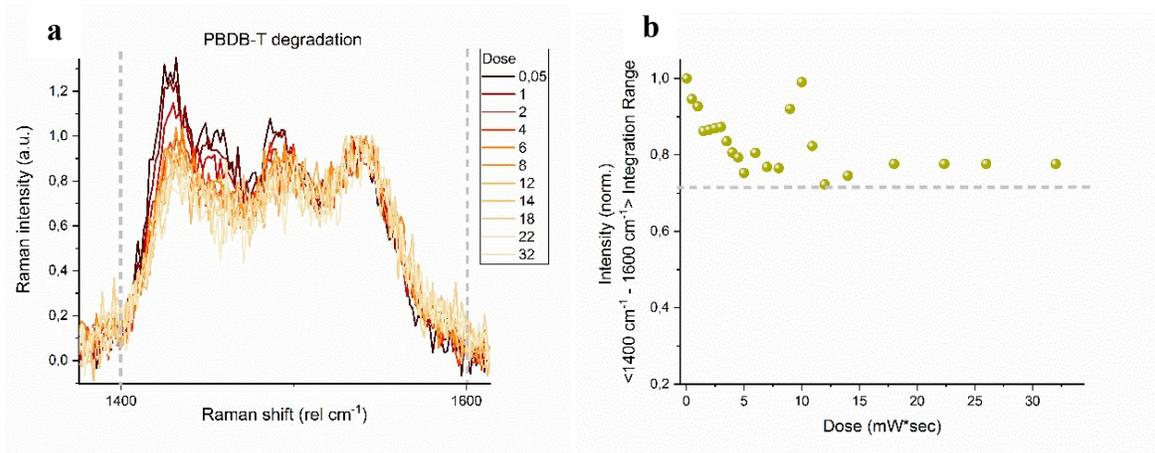


Figure S10. (a) Raman intensity signal acquired with a 488nm laser at different dose intakes, for a PBDB-T donor thin film deposited on top of ZnO. (b) Integrated PBDB-T Raman intensity in the (1400 cm^{-1} - 1600 cm^{-1}) range as a function of the received dose.